

Inventor: Brent A. McClure et al
Title: Capacitor Constructions and Methods of Forming
Assignee: Micron Technology, Inc.
Docket No.: MI22-2067

INFORMATION DISCLOSURE STATEMENT

References – See Attached Form PTO-1449

The citations listed, copies attached, may be material to the examination of the subject application and are therefore submitted in compliance with the duty of disclosure defined in 37 CFR § 1.56. The Examiner is requested to make these citations of official record in this application. No admission is made regarding whether all the submitted references are prior art.

The materials cited are presented to assist in and expedite examination of this application. The present invention is considered to be patentable over the cited materials. Expedited examination and allowance of this application as a patent are therefore urged in order that the public may benefit from the disclosure and commercialization of the invention.

Respectfully submitted,

Dated: 21 Jul 2003 Attorney: James E. Lake
James E. Lake
Reg. No. 44,854

Form PTO-1449 LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)				U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. MI22-2067	SERIAL NO. Filed Herewith	
				APPLICANT Brent A. McClure et al				
				FILING DATE Filed Herewith		GROUP Unknown		
				U.S. PATENT DOCUMENTS				
*Examiner Initial		Document Number	Date	Name		Class	Subclass	Filing Date If Appropriate
	AA	6,180,481	1/01	DeBoer et al				
	AB	6,218,256	4/01	Agarwal				
	AC	6,204,049	8/00	Solayappan				
	AD	6,180,447	1/01	Park				
	AE	6,274,428	8/01	Wu				
	AF	6,124,158	9/00	Dautartas et al				
	AG	6,144,060	11/00	Park				
	AH	5,316,982	5/94	Taniguchi				
	AI	6,281,142	6/99	Basceri et al				
	AJ	6,204,172	9/98	Marsh				
	AK	5,432,732	7/95	Ohmi				
	AL	6,242,299	06/01	Hickert				
FOREIGN PATENT DOCUMENTS								
		Document Number	Date	Country	Class	Subclass	Translation	
	AM						Yes	No
	AN							
	AO							
	AP							
	AQ							
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)								
	AR			A.W. Ott, et al., "Atomic layer controlled deposition of Al ₂ O ₃ films using binary reaction sequence chemistry" Applied Surface Science (107) 1996, pps. 128-136.				
	AS							
EXAMINER				DATE CONSIDERED				
*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.								

Form PTO-1449 U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)				ATTY. DOCKET NO. MI22-2067		SERIAL NO. Filed Herewith		
				APPLICANT Brent A. McClure et al				
				FILING DATE Filed Herewith		GROUP Unknown		
U.S. PATENT DOCUMENTS								
*Examiner Initial		Document Number	Date	Name		Class	Subclass	Filing Date If Appropriate
	AA	6,249,056	06/01	Kwon				
	AB	6,291,289	09/01	Rhodes				
	AC	6,174,770	01/01	Chi				
	AD	5,641,984	06/97	Aftergut et al				
	AE	6,218,260	04/01	Lee et al				
	AF	6,335,240	01/02	Kim et al				
	AG	6,156,606	12/00	Michaelis				
	AH	6,355,519	03/02	Lee				
	AI	5,625,233	04/97	Cabral, Jr. et al				
	AJ	5,126,283	06/92	Pintchovski et al				
	AK	6,420,230	07/02	Derderian et al				
	AL							
FOREIGN PATENT DOCUMENTS								
		Document Number	Date	Country	Class	Subclass	Translation	
							Yes	No
	AM							
	AN							
	AO							
	AP							
	AQ							
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)								
	AR							
	AS							
EXAMINER				DATE CONSIDERED				
*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.								

Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE			ATTY. DOCKET NO. MI22-2067	SERIAL NO. Filed Herewith		
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)					APPLICANT Brent A. McClure et al			
					FILING DATE Filed Herewith		GROUP Unknown	
U.S. PATENT DOCUMENTS								
*Examiner Initial		Document Number	Date	Name		Class	Subclass	Filing Date If Appropriate
	AA	2001/0024387A1	09/01	Raaijmakers et al				
	AB	2002/0064915A1	05/02	Kitamura				
	AC	2001/0023110A1	09/01	Fukuzumi et al				
	AD	09/653,156		Agarwal (as filed and amended)				08/00
	AE	09/653,149		Derderian (as filed and amended)				08/00
	AF							
	AG							
	AH							
	AI							
	AJ							
	AK							
	AL							
FOREIGN PATENT DOCUMENTS								
		Document Number	Date	Country	Class	Subclass	Translation	
							Yes	No
	AM							
	AN							
	AO							
	AP							
	AQ							
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)								
	AR							
EXAMINER				DATE CONSIDERED				
<p>*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.</p>								